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| <p>Searched</p>  | <p>Application/Control No.</p> <p>10526643</p> | <p>Applicant(s)/Patent Under Reexamination</p> <p>SAEKI, TETSUO</p> |
| | <p>Examiner</p> <p>ALLI, IYABO S</p> | <p>Art Unit</p> <p>2112</p> |

| Class | SubClass | Date | Examiner |
|--|-----------------|--------------------|----------|
| 356 | 445-446,311-318 | | |
| 362 | 253 | | |
| F21V33 | 00 | | |
| 359 | 569 | | |
| 250 | 216 | | |
| inventor name search: saeki-tetsuo.in. | | | |
| text searched: transparent with substrate and then with ridge and plasmon\$3 | | | |
| text searched: plasmons | | | |
| text searched: copper, gold, and silver | | | |
| text searched: evanescent with waves | | | |
| text searched: photodetect\$4 | | | |
| inventor name search: naya.in | | | |
| text searched: convergent with light | | | |
| text searched: plasmon\$4 and microscope | | | |
| U.S. Patent and Trademark Office | | Part of Paper No.: | |

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| Search Notes  | Application/Control No. 10526643 | Applicant(s)/Patent Under Reexamination SAEKI, TETSUO |
| | Examiner ALLI, IYABO S | Art Unit 2112 |

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| Notes | Date | Examiner |
| PLUS [PLUS2@uspto.gov] | 9/6/2006 | |
| U.S. Patent and Trademark Office | Part of Paper No.: | |